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Measure methods of semiconductor light emitting diodes

半导体发光二极管测试方法

(English Translation)

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What this standard covers

This standard specifies the electrical characteristics of the semiconductor light-emitting diode test method, the optical characteristics of test methods, optical characteristics test method, the color characteristics of test methods, test methods and thermal characteristics of electrostatic discharge sensitivity testing methods.

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Standards quoted by this document

GB/T 3977-2001; GB/T 4365-2003; GB/T 5698-2001; GB/T 5702-2003; GB/T 7921-1997; GB/T 7922-2003; GB/T 11499-2001; GB/T 15651-1995; CIE 127-1997; ANSI/ESD STM 5.1-2001; ANSI/ESD STM 5.2-1999